

Notice of References Cited	Application/Control No. 10/564,833		Applicant(s)/Patent Under Reexamination HAMANO ET AL.	
	Examiner FRANK D. DUCHENEAUX		Art Unit 1794	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0173940	09-2004	Yuhara et al.	264/259
*	B	US-2003/0183495	10-2003	Kashino, Masayuki	200/341
*	C	US-2004/0251634	12-2004	Shimazu et al.	277/434
*	D	US-2001/0040001	11-2001	Toyooka, Naoto	156/233
*	E	US-5,824,252	10-1998	Miyajima, Fumio	264/272.17
*	F	US-2005/0116386	06-2005	Hamano et al.	264/279
*	G	US-4,917,927	04-1990	Sakaitani et al.	428/42.1
*	H	US-5,922,369	07-1999	Yanagihara et al.	425/572
*	I	US-2001/0038493	11-2001	Watanabe et al.	359/609
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 03013823 A1	02-2003	World Intellect	KURAMITSU M et al.	B29C 45/14
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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